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50B. Application Reliability

Session Date:	March 10(Fri.), 2023
Session Time:	10:40-11:50
Session Room:	Room B (#307 bc)
Session Chair:	Dr. Jin-Woo Han (Samsung Electronics Co., Ltd)

[50B-1] [Invited] **10:40-11:05**

Reliable Resistive Switching of Janus Graphene Oxide Based Memristive Crossbar Array

Fei Hui[1], Conghui Zhang[1], Tingting Han[2], Mario Lanza[3] and Peisong Liu[4]

[1]Zhengzhou University, [2]Soochow University, [3]King Abdullah University of Science and Technology, [4]Henan University

[50B-2] **11:05-11:20**

Demonstration of a Junctionless Negative Capacitance FinFET-Based Hydrogen Gas Sensor: A Reliability Perspective

Navneet Gandhi[1], Rajeewa Kumar Jaisawal[1], Sunil Rathore[1], P. N. Kondekar[1], Shashank Banchhor[2] and Navjeet Bagga[3]

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[50B-3] **11:20-11:35**

Electro-Thermal Properties and Self-Heating Effect in Multi-Nanosheet FETs: Junctionless Mode versus Inversion Mode

Nitish Kumar, Kanyakumari Ashok Bhinge, Ankur Gupta and Pushpapraj Singh

Indian Institute of Technology Delhi

[50B-4] **11:35-11:50**

Cross-Temperature Reliabilities in TLC 3D NAND Flash Memory: Characterization and Solution

Yifan Guo, Kenie Xie, Xiaotong Fang, Xuepeng Zhan, Jixuan Wu and Jiezhi Chen

Shandong University